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# Ensuring Success in High-Speed System Design

# Today's-High Speed Systems

- High-Speed Designs Require Faster Devices & Increasing Data Widths
- Wide Data Buses Demand Higher I/O Pin Count
- Faster Devices Exhibit Faster Edge Rates
- A Memory Interface is a Typical Example for Such a System

# Agenda

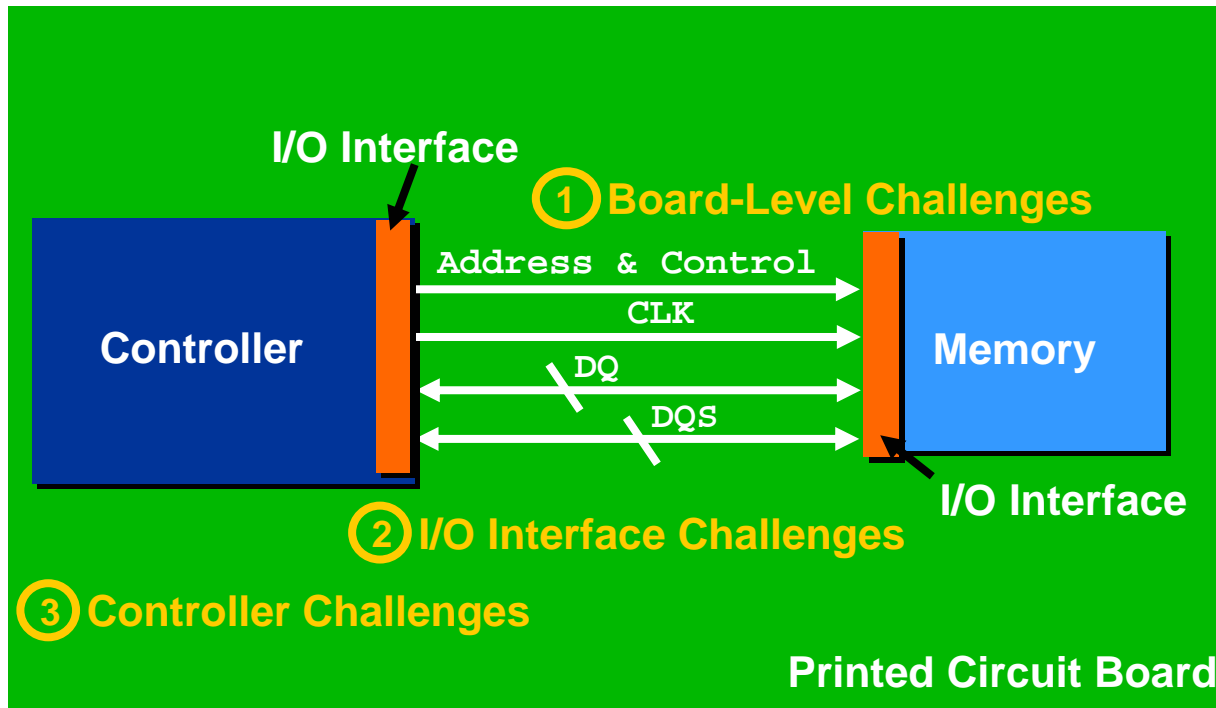
- Memory Interface Design
- Simultaneously Switching Outputs
- Altera Design Resources
- References



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# Memory Interface Design

# Memory Interface Design Challenges

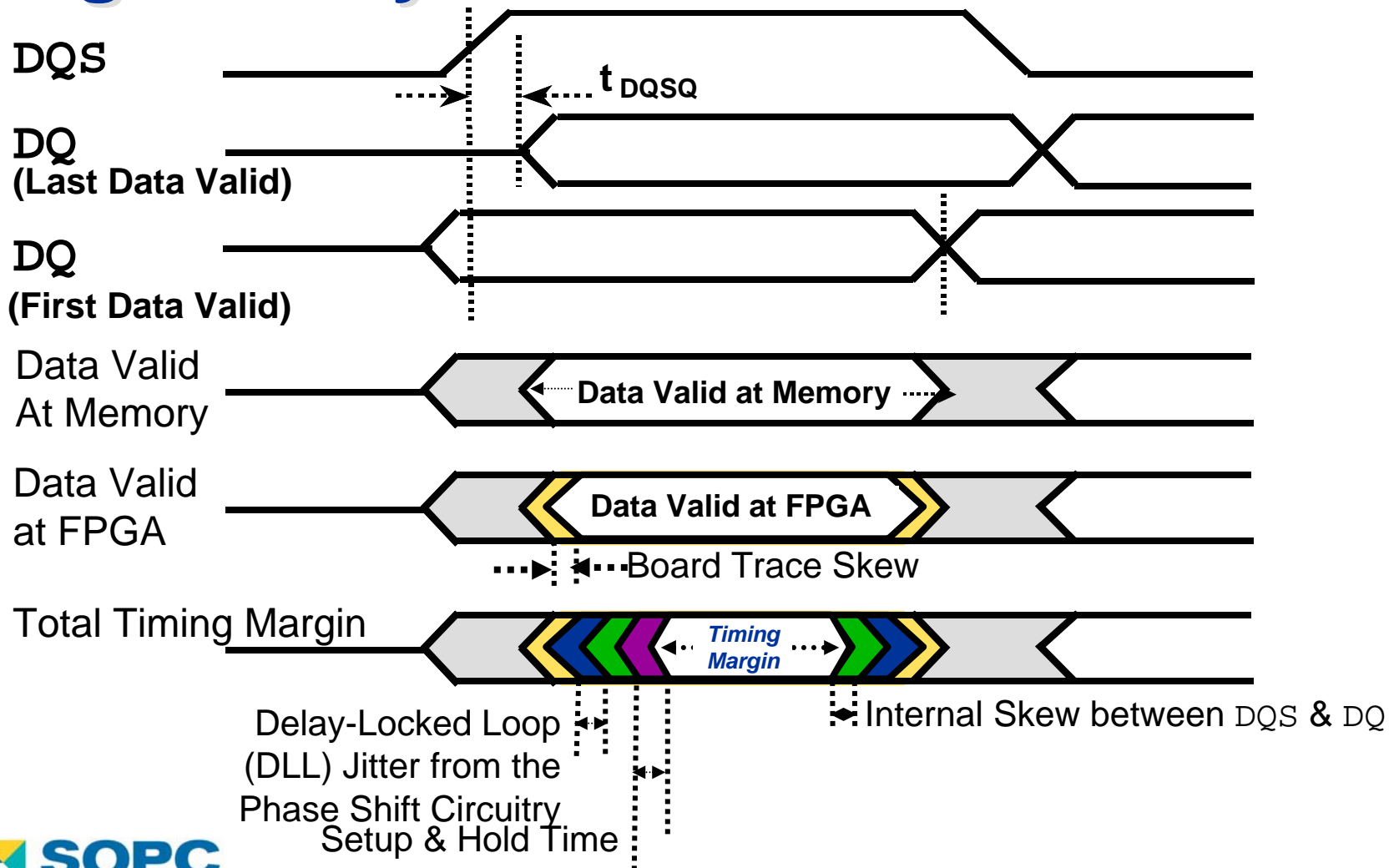


*The Higher the Frequency, the Greater the Design Challenge*

# Altera Memory Interface Solutions

Challenge	Altera Resolution
<b>Board-Level Challenges</b>	<ul style="list-style-type: none"><li>■ Simultaneous Switching Outputs (SSO) Guidelines</li><li>■ Fully Verified Hardware Reference Platforms with Gerber Files</li><li>■ Termination Recommendations &amp; Board Design Guidelines</li><li>■ SPICE &amp; IBIS I/O Simulation Models</li></ul>
<b>I/O Interface Challenges</b>	<ul style="list-style-type: none"><li>■ DQS Phase Shift Circuitry in Stratix® Series FPGAs</li><li>■ Detailed Timing Margin Analysis for Non-IP Users</li><li>■ Fully Optimized Memory Controller Intellectual Property (IP) Cores with Automatic Timing Analysis for IP Users</li></ul>
<b>Controller Design Challenges</b>	<ul style="list-style-type: none"><li>■ Fully Optimized Memory Controller IP Cores with Automatic Timing Analysis &amp; Functional Simulation Capabilities</li><li>■ Feature-Rich Phase-Locked Loops (PLLs) to Manage Clocks</li></ul>

# Example: DDR2 Read Timing Margin Analysis



# Signal Integrity & Board Design

Design Item	Effect on Performance/Reliability of the System
<b>Bus Width</b>	Increasing Bus Width Increases SSO Noise & also Increases Board Design Complexity
<b>Noise</b>	Causes Bit Errors, Effects Signal Integrity & Degrades Performance & Reliability
<b>Loading</b>	Increasing Number of Devices or Modules will Reduce Performance
<b>Termination Scheme</b>	Termination Scheme & Resistor Values Affect Signal Quality & Performance

*Board Simulations Should be Performed to Check for Signal Integrity*



# Simultaneously Switching Outputs

- Increased Bus Width, Pin I/O Counts & Inherent Package Trade-Offs Can Introduce More SSO Noise
  - I/O Count vs. I/O Drive Strength
- An FPGA Offers the Flexibility to Employ Reduction Techniques to Minimize Detrimental Effects of SSO



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# Simultaneous Switching Outputs (SSO)

# Components of SSO Noise

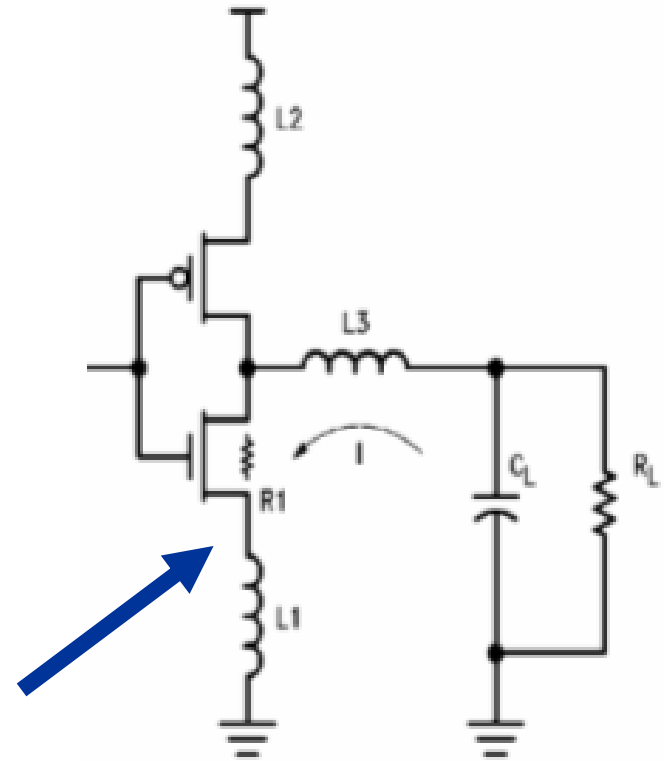
- Ground Bounce
- Power Bounce Commonly Referred to as Vcc Sag

# What is SSO Noise?

- Ground Bounce & Vcc Sag are Voltage Fluctuations on a Static Signal (Quiet) as a Result of High Current Change ( $di/dt$ ) from Nearby I/O Buffer Circuitry that Share Common Ground (Vcc) Return Paths
- Ground Bounce Affects Static Low Signals; Vcc Sag Affects Static High Signals
- Enough Ground Bounce or Vcc Sag on a Static Signal May Cause Sampling of Wrong Data, Depending on:
  - I/O Standard Used
  - Available Noise Margin
  - Amount of Ground Bounce
  - When the Signal is Sampled

# Ground Bounce Circuit Model

- L1 is Lumped Inductance for Die, Bump, Package, & Ball
- Output Buffer Current  
 $i(t) = C * dv/dt$
- Voltage Across L1  
 $v(t) = L * di/dt$
- High-to-Low Transitions on Output Raises Local Ground V



# Ground Bounce Circuit Model

- Key Equations

$$i(t) = C \cdot dv/dt$$

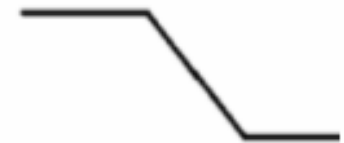
$$v(t) = L \cdot di/dt$$

- Output Voltage (b) with Certain Slew Rate

- Induces Current (c) through Pull-Down Transistor & L1

  - Ideal Waveform

- Creates Voltage Ground Bounce (d) in Local Ground, through Other Quiet Low Outputs via NMOS Transistors



b. Output Voltage (V)



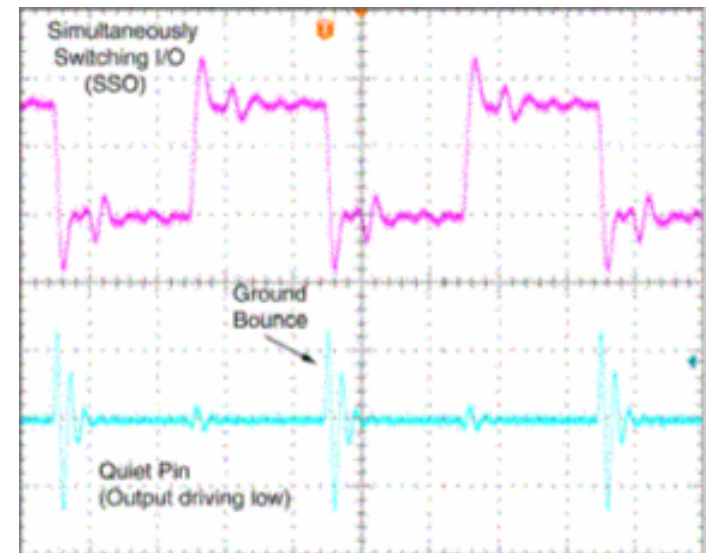
c.  $I = -C_L \cdot (\Delta V/\Delta t)$



d.  $V_{GB} = L \cdot (dI/dt)$

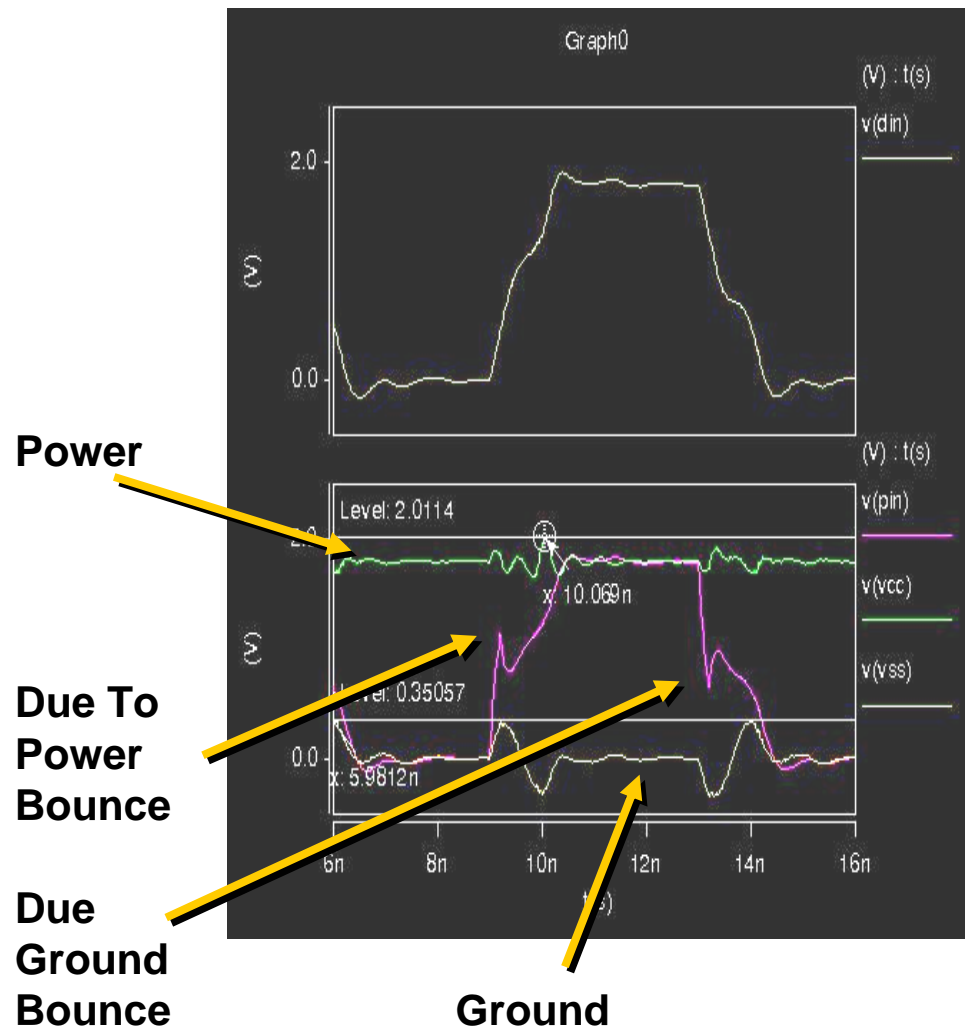
# Impact of Ground Bounce (cont.)

- If Enough Outputs Switch Simultaneously to Induce 0.8V of Ground Bounce on a Nearby “Victim” Pin, that Pin Momentarily Glitches to 0.8V
  - 3.3-V LVTTL, Maximum  $V_{IL}$  is 0.7V
- If Victim Pin is Clocked During the SSO Event, the Sampled Value May Be Wrong
  - Similarly Applies to Vcc Sag &  $V_{IH}$  Minimum.



# Impact of Ground Bounce

- Ground Bounce
  - Effects Worse than Power Bounce
  - Can Cause Logic 1 Instead of 0 in Extreme Cases
- Vcc Sag
  - Causes Drop in Power Supply
  - Can Affect Outputs
- Both Cause Degradation in Waveforms





# Elements That Contribute To SSO Noise

- Package:
  - Number of Power/Ground Pins
  - Reference Planes
  - Decoupling
  - Package Type (Flip-Chip vs. Wirebond)
    - Majority of SSO Noise Occurs at Package Level
- Board:
  - Decoupling Capacitors
  - Power Ground Planes
  - Sockets
  - Vias

# Packaging

- Wire-Bond: Lacks Referencing Structures for Every Signal Trace, thus Contributes to Overall High Inductance
- Flip-Chip: Signal Bumps Enter the Package Laminate without Having to Traverse through Long, Unreferenced Wire-Bonds

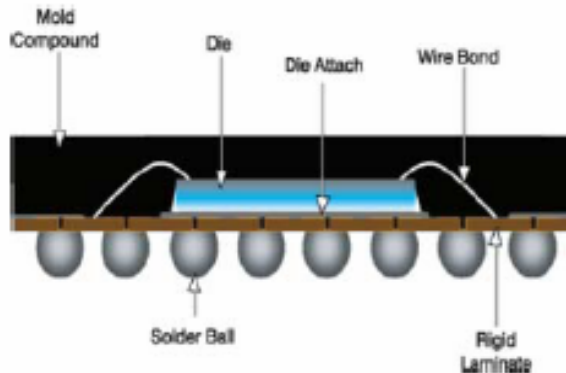


Figure 1.6 - Wire bond package cross section

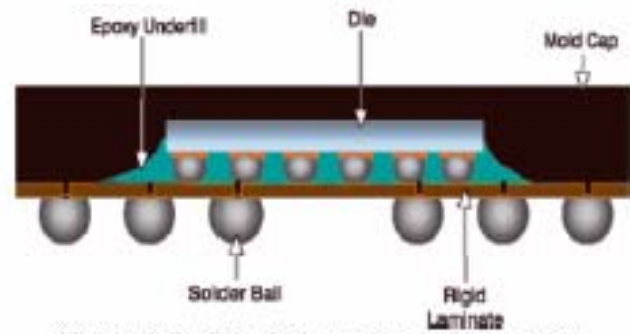
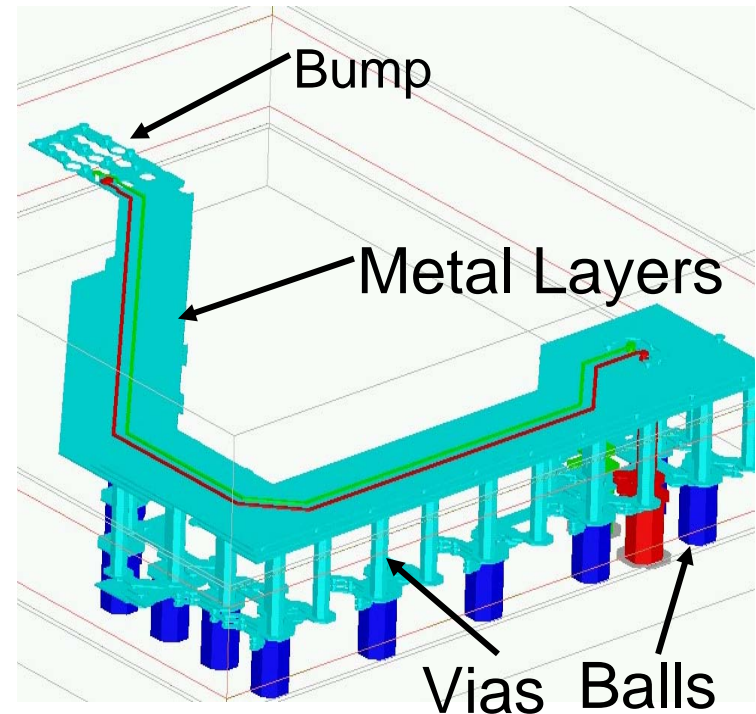
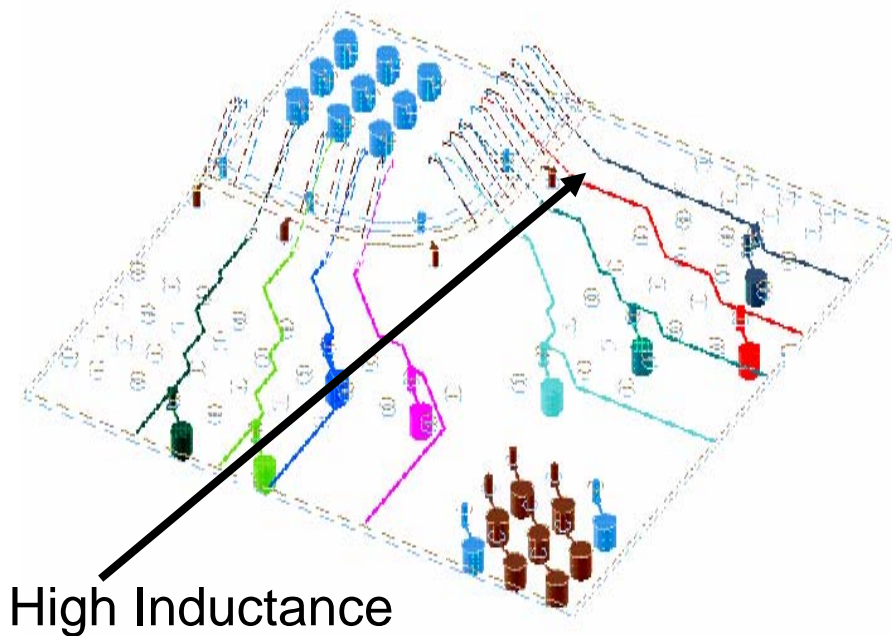


Figure 1.7 - Flip Chip package cross section

# Packaging

## *Flip-Chip Vs. Wire-Bond*



# Techniques For Reducing SSO Noise

- Use Flip-Chip Package
- Add/Utilize Better Return Paths
  - Use Unused I/O Pins as Programmable Vcc & GND
- Use Lower Drive Strength
- Use Slow Slew Rate (SSR) vs. Fast Slew Rate (FSR)
- Proper I/O Pin Selection
- Add Decoupling Capacitors & on Board Power Ground Capacitance
- Proper Trace Layout
- Remove Sockets
- Use On-Chip Termination

*All Techniques Verified Using  
Stratix<sup>®</sup> & Stratix GX Reference Boards*

# Utilize Unused I/O Pins as Programmable Vcc & GND

# of I/O Pins Switching	Ground Bounce (mV)	Vcc Sag (mV)
20: All Pins Switching	650	1,020
20: Every Other I/O Pin switching	490	910
20: Every Other I/O Pin Switching & Every Other Tied to Ground	364	820
20: Every Other I/O Pin Switching & Every Other Tied to Power	490	700
24: Every Third I/O Pin Switching, Every Third Tied to Power & Every Third Tied to Ground	300	320

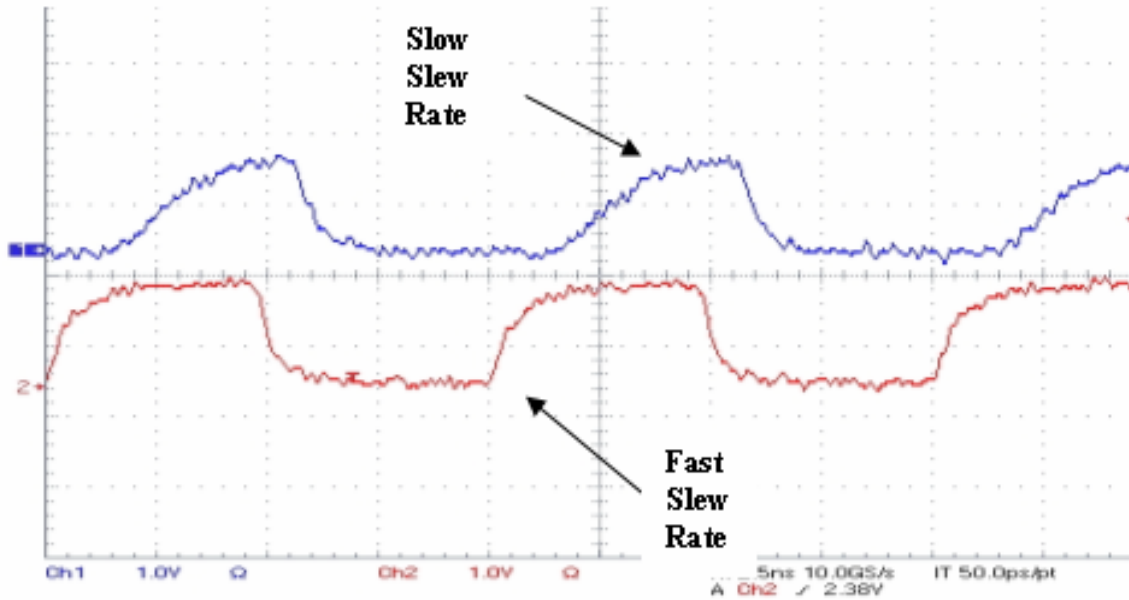
*Results For 24 mA LVTTTL I/O Pins*

# Use Lower Drive Strength

# of I/O Pins Switching	Drive Strength	Ground Bounce (mV)	Vcc Sag (mV)
20: All I/O Pins Switching	24 mA	650	1,020
20: All I/O Pins Switching	12 mA	456	730
20: All I/O Pins Switching	4 mA	328	660

*Results For LVTTTL I/O Pins*

# Turn on Slow Slew



8 mA Drive Strength,  $\longrightarrow$   
 40 3.3-V LVTTTL I/O Pins,  
 Switching Simultaneously

Switching	With Fast Slew Rate	With Slow Slew Rate
Bounce (mV)	288	200
Vcc Sag (mV)	620	310

# Delay Shift SSO pins

	18	19	20	21	22	23	24	25	26	27	28	29	30	31	32
A		VCCN	VSS	A21	A22	A23	A24	A25	A26	A27	A28	A29	VCCN	VSS	
B			B20	B21	B22	B23	B24	B25	B26	B27	B28	B29	B30	B31	VSS
C			C20	C21	C22	C23	C24	C25	C26	C27	C28	C29	C30	C31	
D			D19	D20	D21	D22	D23	D24	D25	D26	D27	D28	D29	D30	
E			E19	E20	E21	E22	E23	E24	E25	E26	E27	E28	E29	E30	
F			F19	F20		F23	F24	F25	F26	F27	F28	F29	F30		
G				G21		G23	G24								
H				H21		H23									
J					J22	J23									
K						K23									
L							L23								
M								M23							
N		VCCN	VSS	VCCN	VSS			VSS							

825mV

	18	19	20	21	22	23	24	25	26	27	28	29	30	31	32
A		VCCN	VSS	A21	A22	A23	A24	A25	A26	A27	A28	A29	VCCN	VSS	
B			B20	B21	B22	B23	B24	B25	B26	B27	B28	B29	B30	B31	VSS
C			C20	C21	C22	C23	C24	C25	C26	C27	C28	C29	C30	C31	
D			D19	D20	D21	D22	D23	D24	D25	D26	D27	D28	D29	D30	
E			E19	E20	E21	E22	E23	E24	E25	E26	E27	E28	E29	E30	
F			F19	F20		F23	F24	F25	F26	F27	F28	F29	F30		
G				G21		G23	G24								
H				H21		H23									
J					J22	J23									
K						K23									
L							L23								
M								M23							
N		VCCN	VSS	VCCN	VSS			VSS							

420mV

40% Average Reduction!

32 SSO, w/ 8 pins delayed by 3ns (in yellow)

- Reduces Current Density
- Add PLL Phase Shift, or Add Output Timing Delays



# Spread Out Selected I/O Pins

	18	19	20	21	22	23	24	25	26	27	28	29	30	31	32
A		VCCN	VSS	A21	A22	A23	A24	A25	A26	A27	A28	A29	VCCN	VSS	
B			B20	B21	B22	B23	B24	B25	B26	B27	B28	B29	B30	B31	VSS
C			C20	C21	C22	C23	C24	C25	C26	C27	C28	C29	C30	C31	
D		D19	D20	D21	D22	D23	D24	D25	D26	D27	D28	D29	D30		
E		E19	E20	E21	E22	E23	E24	E25	E26	E27	E28	E29	E30		
F		F19	F20			F23	F24	F25	F26	F27	F28	F29	F30		
G				G21		G23	G24								
H				H21		H23									
J					J22	J23									
K						K23									
L						L23									
M						M23									
N		VCCN	VSS	VCCN	VSS		VSS								

**Bounce = 570**  
**Sag = 1,017 mV**

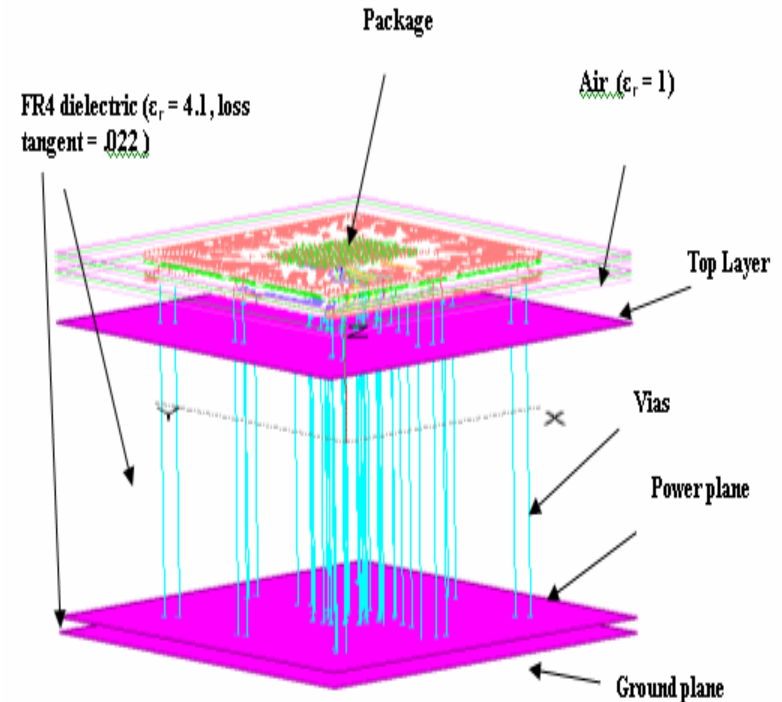
	18	19	20	21	22	23	24	25	26	27	28	29	30	31	32
A		VCCN	VSS	A21	A22	A23	A24	A25	A26	A27	A28	A29	VCCN	VSS	
B			B20	B21	B22	B23	B24	B25	B26	B27	B28	B29	B30	B31	VSS
C			C20	C21	C22	C23	C24	C25	C26	C27	C28	C29	C30	C31	
D		D19	D20	D21	D22	D23	D24	D25	D26	D27	D28	D29	D30		
E		E19	E20	E21	E22	E23	E24	E25	E26	E27	E28	E29	E30		
F		F19	F20			F23	F24	F25	F26	F27	F28	F29	F30		
G				G21		G23	G24								
H				H21		H23									
J					J22	J23									
K						K23									
L						L23									
M						M23									
N		VCCN	VSS	VCCN	VSS		VSS								

**Bounce = 412**  
**Sag = 810 mV**

# On-Board Power Ground Capacitance

## ■ Solid Power & Ground Planes

Configuration	Ground Bounce
Ground/Power, 140 mils from IC, 6 mils Apart	370 mV
Ground/Power, 20 mils from IC, 6 mils Apart	248 mV
Ground/Power, 20 mils from IC, 4 mils Apart	228 mV



# Decoupling Capacitors

- Decoupling Capacitors Provide Localized Power Supply
  - Capacitance Stores Energy & Provides It When There Is Transient Requirement
- When Solid Power/Ground Sandwich Present, High Frequency on Board Capacitors Can Be Useless if Path to IC Is Very Inductive
- Bigger Capacitors Are Effective for Lower Frequency Noise

*Stratix II FPGAs Offer On-Chip Decoupling,  
an Optimal Solution to Provide  
Better Return Paths*

# Other Techniques

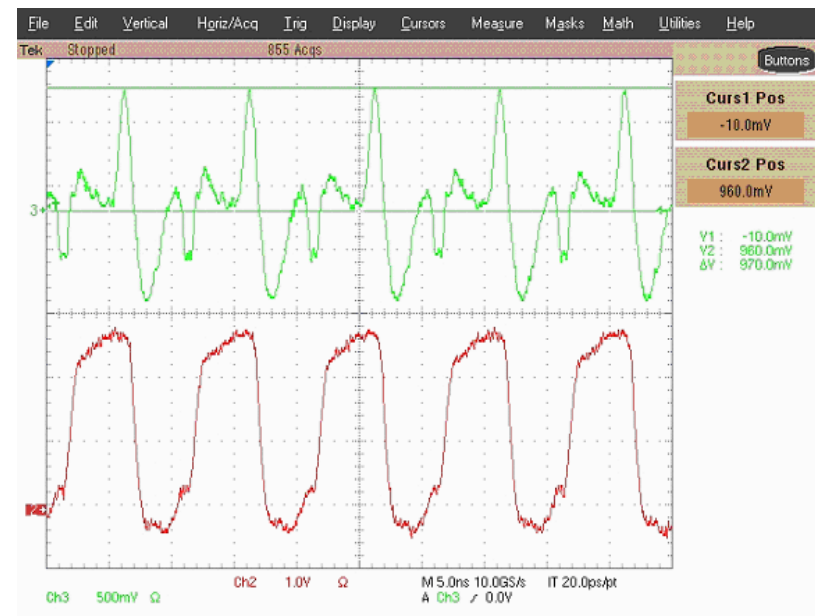
- Don't Use Any Sockets between IC & Board
  - Reduces Inductance
- Differential Signaling Helps with SSO
  - Traces Should Be Tightly Coupled
- Series On-Chip Termination Reduces SSO by Absorbing Reflections
  - Slows Edge Rate

# Worst Case (Before Optimization)

- Combination of Several Factors Can Significantly Reduce Ground Bounce & Vcc Sag Noise

	18	19	20	21	22	23	24	25	26	27	28	29	30	31	32
A		VCCN	VSS	(A21)	A22	(A23)	(A24)	(A25)	A26	A27	A28	A29	VCCN	VSS	
B			(B20)	(B21)	(B22)	(B23)	(B24)	(B25)	B26	B27	B28	B29	B30	B31	VSS
C			(C20)	(C21)	(C22)	(C23)	(C24)	(C25)	C26	C27	C28	C29	C30	C31	
D		(D19)	(D20)	(D21)	(D22)	(D23)	(D24)	(D25)	D26	D27	D28	D29	D30		
E		(E19)	(E20)	(E21)	(E22)	(E23)	(E24)	(E25)	E26	E27	E28	E29	E30		
F		(F19)	(F20)			F23	F24	F25	F26	F27	F28	F29	F30		
G				G21		G23	G24								
H				H21		H23									
J					J22	J23									
K							K23								
L							L23								
M							M23								
N		VCCN	VSS	VCCN	VSS		VSS								

**970mV**



*40 SSO Pins, 24-mA Current Drive, FSR, No Delay, No Programmable Grounds*

# Nominal Case

	18	19	20	21	22	23	24	25	26	27	28	29	30	31	32
A		VCCN	VSS	A21	A22	A23	A24	A25	A26	A27	A28	A29	VCCN	VSS	
B			B20	B21	B22	B23	B24	B25	B26	B27	B28	B29	B30	B31	VSS
C			C20	C21	C22	C23	C24	C25	C26	C27	C28	C29	C30	C31	
D		D19	D20	D21	D22	D23	D24	D25	D26	D27	D28	D29	D30		
E		E19	E20	E21	E22	E23	E24	E25	E26	E27	E28	E29	E30		
F		F19	F20			F23	F24	F25	F26	F27	F28	F29	F30		
G				G21		G23	G24								
H				H21		H23									
J					J22	J23									
K						K23									
L						L23									
M						M23									
N		VCCN	VSS	VCCN	VSS		VSS								

430mV



40 SSO Pins, 36 Interleaved Programmable Powers (Red) & Grounds (Green), 16-mA Current Drive, FSR, 22 Pins with 3-ns Delay (Yellow)

# Best Case

	18	19	20	21	22	23	24	25	26	27	28	29	30	31	32
A		VCCN	VSS	A21	A22	A23	A24	A25	A26	A27	A28	A29	VCCN	VSS	
B			B20	B21	B22	B23	B24	B25	B26	B27	B28	B29	B30	B31	VSS
C			C20	C21	C22	C23	C24	C25	C26	C27	C28	C29	C30	C31	
D		D19	D20	D21	D22	D23	D24	D25	D26	D27	D28	D29	D30		
E		E19	E20	E21	E22	E23	E24	E25	E26	E27	E28	E29	E30		
F		F19	F20			F23	F24	F25	F26	F27	F28	F29	F30		
G				G21		G23	G24								
H				H21		H23									
J					J22	J23									
K						K23									
L						L23									
M						M23									
N		VCCN	VSS	VCCN	VSS		VSS								

70mV!



40 SSO Pins Far Away, 36 Programmable Powers (Red) & Grounds (Green) around Quiet Pin, 4-mA Current Drive, SSR, 20 Pins with 3-ns Delay



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# Altera Design Resources





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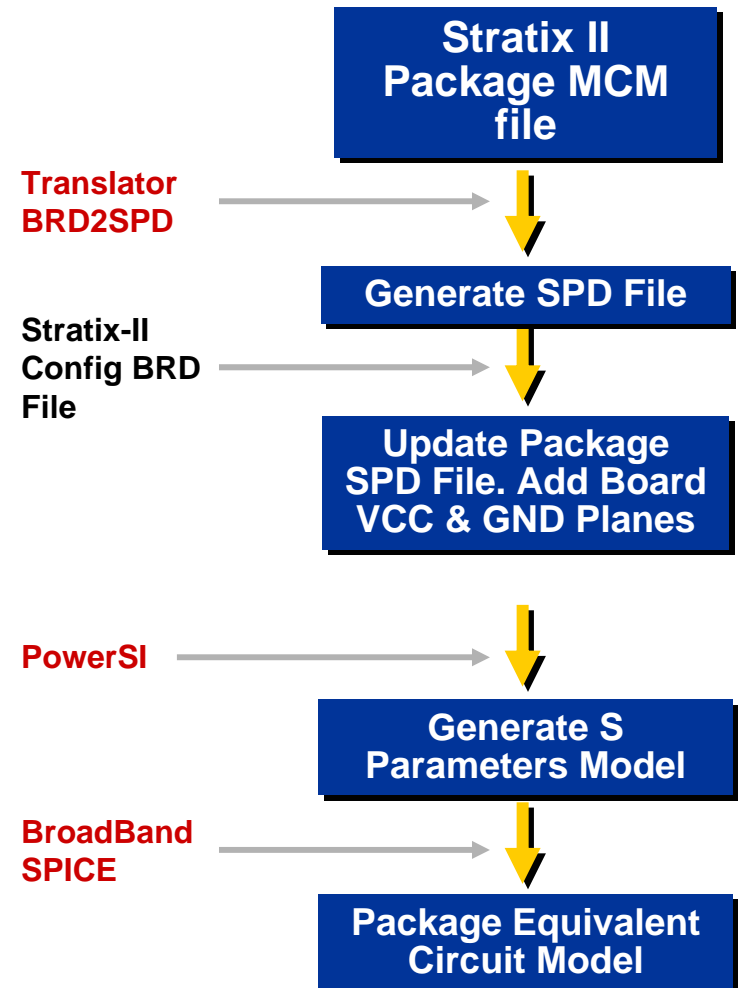
# Modeling

# Objective of SSO Modeling

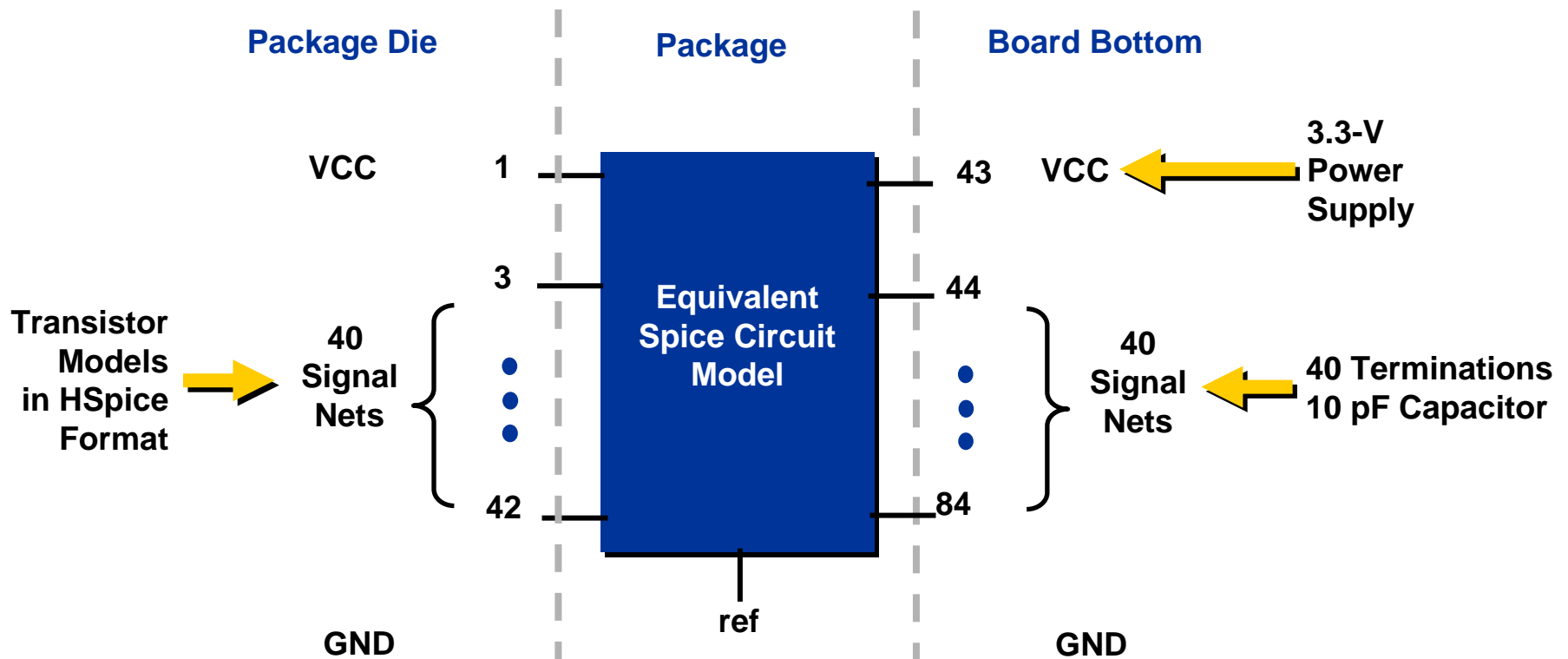
- Explore, Derive & Verify a Robust Methodology that Can Be Consistently Used in Future SSO Analysis
- Simulate & Correlate the Results Obtained from Lab Measurements
- Generate & Validate Simulation Models that Can Be Used as a Black Box for ‘what-if’ Analysis

# SSO Model Extraction Flow

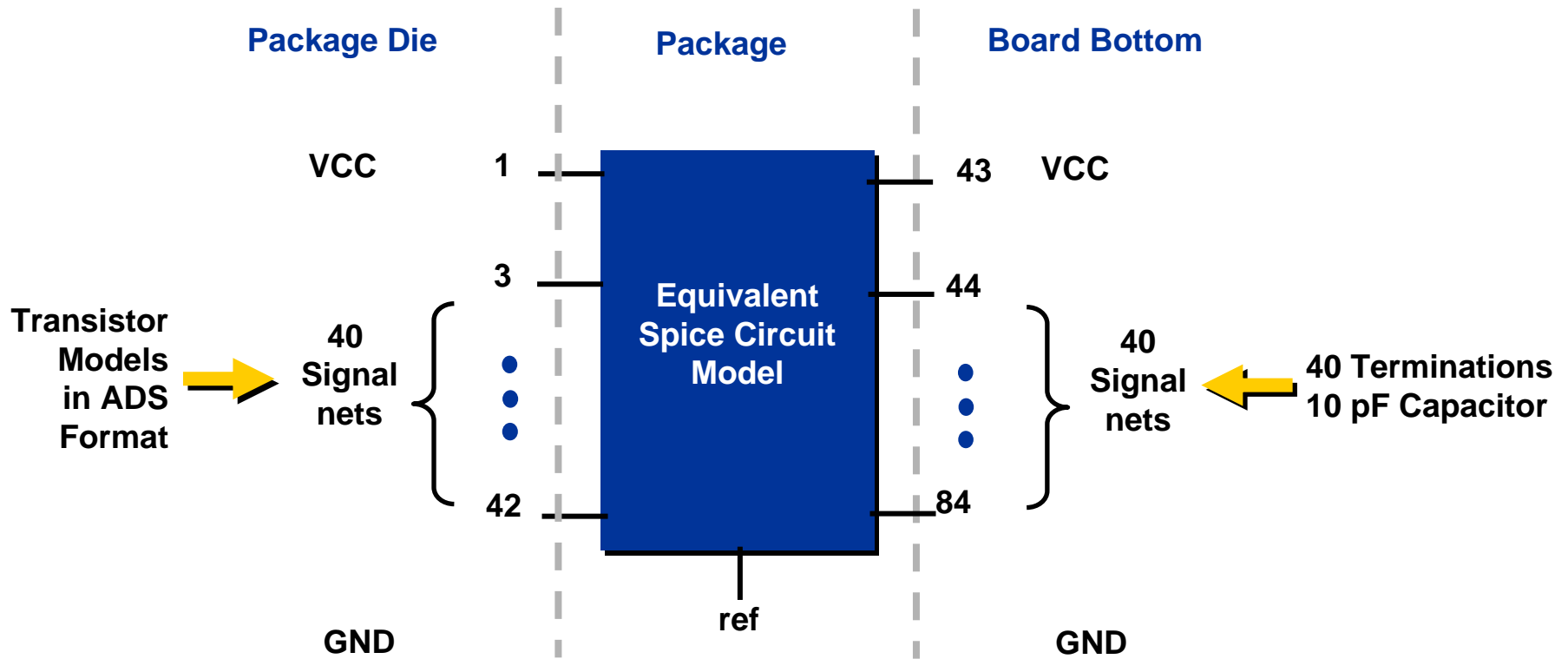
- Translation of Database
  - Translate Package MCM File into Sigrity SPD Format
- Structure Verifications/Modifications
  - Verify Stackup, Material Properties, Plane Shape, Via/Trace Dimensions
  - Add Board VCC & Ground Planes
  - Others
- Mesh Settings
  - Add Solder Ball Vias
- Error Corrections
- Coupled Line Selection
- Define Ports
- Pre-Simulations Tests
  - DC Test
  - AC Test
  - Signal Transmission Test



# Simulation Flow Using HSpice



# Simulation Flow Using ADS (Optional)



The Simulation Flow Will Be Updated after ADS Model Becomes Available.

# SSO Modeling Matrix Chart

Task	Number of I/O Pins				Current Strength				I/O Location			
	1	10	40	Max	Min	Typ	Max		VIO	HIO	SSTL2	LVTTTL3.3V
SSN Measurement	●	●	●	●	●	●	●	●	●	●	P1	P1
SSO Timing Push Out	●		●	●	●		●	●	●		P1	P1
SSO vol/voh Violation	●		●	●	●		●	●	●		P1	P1
<b>Vref</b>	●		●	●	●		●	●	●	●	P1	
Programmable Power/GND Ppins			●			●		●	●	●	P1	P1
			●			●		●	●			●
<b>Individual vs. Adjacent Banks</b>			●			●		●	●	●		●
Distribution of I/O Pins			●			●		●	●	●	●	●
SSN Measurement												

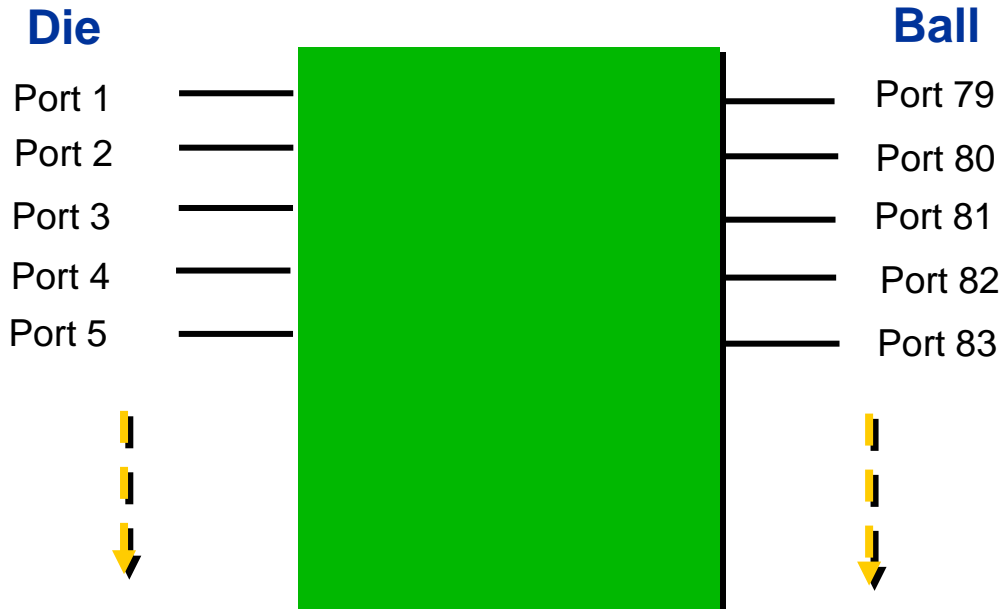
# HSpice Models

- Encrypted HSpice Models For All I/O Pins
- Models Are Accompanied by Correlation Report & User Guide
- Package Models:
  - Distributed Models
  - Lumped Models

# SSO Kit

- S-Parameter Models Using Sigrity Power SI
- HSpice Models Derived From S-Parameter Models Using Broadband Spice

HSpice  
Sub-Circuit  
Call



```
.subckt ss 1 2 3 4 5 6 7 8 9 10 11 12 13
          14 15 16
+17 18 19 20 21 22 23 24 25 26 27 28
          29 30 31
+32 33 34 35 36 37 38 39 40 41 42 43
          44 45 46 47
+48 49 50 51 52 53 54 55 56 57 58 59
          60 61 62 63
+64 65 66 67 68 69 70 71 72 73 74 75
          76 77 78 79
+80 81 82 83 84 85 86 87 88 89 90 91
          92 93 94 95
+96 97 98 99 100 101 102 103 104 105
          106 107 108 109
+110 111 112 113 114 115 116 117 118
          119 120 121 122
+123 124 125 126 127 128 129 130 131
          132 133 134 135
+136 137 138 139 140 141 142 143 144
          145 146 147 148
+149 150 151 152 153 154 155 156 ref
```



# Other Modeling Collateral

## ■ HSpice Kit

- Library Of Transmission Line Models, Via Models & Connector Models, Correlated with Lab Measurements



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# Design Services Partner Program



# Premise Behind Partner Program

- Altera Partners with Best-in-Class Engineering Firms to Provide Altera–Based Design Services for Mutual Customers
- Altera’s Motivation
  - Expand Technical Resource Base
- Partner’s Motivation
  - Worldwide Co-Marketing
  - Access to a Large Sales Channel
  - Access to Worldwide Customers

# Benefits to Customers

**Single Contact Point**

**Focus on  
Specification**

**Reduced  
Time-to-Market**

**Access to Expertise  
Improves System  
Performance**

# Characteristics of Partners

- Altera Partners with Only the Best & Partners Are Limited in Number
- Characteristics of Partners:
  - Aligned Along Vertical Market Segments
  - Expertise at Architectural Level (Not at Socket Level)
  - Identified as Being Leaders in Their Segment
  - Significant Size & Financially Secure for Credibility
  - Already Known & Trusted by Customers
  - Worldwide Position
  - No Universal Pricing Method, Pricing Negotiated between Customer & Consultant
  - Supports Customer Directly

For More Information, Log onto [www.altera.com](http://www.altera.com), or  
Speak to Your Local Altera Sales Representative



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# Additional Altera Resources

# Memory Interface Standard Deliverables

## Handbook

- Device Description
- Electrical Parameters
- Device Timing



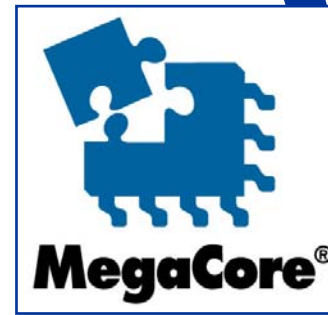
## Application Note

- Interface Description
- Timing Analysis
- Electrical Analysis



## Demonstration Board

- Demonstration Project
- Board Layout Guidelines
- Schematics/Gerbers
- Signal Integrity Analysis
- Documentation



- User Interface
- Open Source Datapath
- System Timing Analysis
- Reference Design
- Constraints
- User Guide



- Compilation Support
- Timing Models

# Memory Solutions Center

[Home](#) > [Technology Center](#) > [Memory](#)

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## Memory Solutions Center

The Memory Solutions Center provides all the resources needed for designing memory interfaces with Altera® FPGAs. Available resources include technical documentation, software and tool support, characterization reports, intellectual property (IP) cores and reference designs, demonstration boards, and simulation models.

### DRAM


- [DRAM Devices Overview](#)
- [DDR SDRAM](#)
- [DDR2 SDRAM](#)
- [RLDRAM II](#)
- [SDR SDRAM](#)

### SRAM


- [SRAM Devices Overview](#)
- [QDR/QDR II SRAM](#)
- [ZBT SRAM](#)

### Embedded Memory


- [Embedded Memory](#)



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*Web Site to Provide Easy Access to Memory Support Information*



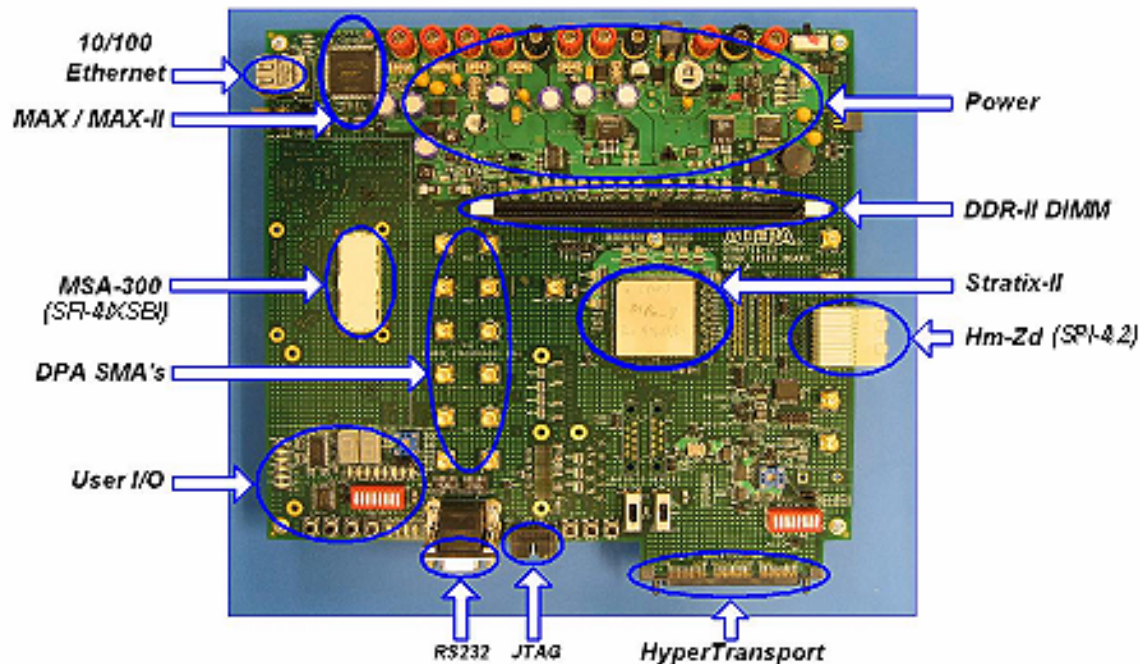
# Benefits of Altera's Memory Solution

- Simplifies Memory Interface Design Process
  - Dedicated Circuitry in Silicon, Software & Tool Support
- Ensures First-Time Design Success
  - Hardware Reference Platform for Design Verification
- Reduces Design Cycles
  - IP Core Support, Detailed Documentation

*Complete System-Level  
Solution*

# Stratix II High-Speed Development Board

- Designed for the Development of Applications that Incorporate High-Performance Interfaces
  - Stratix II EP2S60F1020C3 FPGA
  - External Connectors for a Broad Array of Applications



# More Information

- Simultaneous Switching I/O Noise Guidelines for Stratix & Stratix GX FPGAs
- Minimizing Ground Bounce & Vcc Sag  
[http://www.altera.com/literature/wp/wp\\_grndbnce.pdf](http://www.altera.com/literature/wp/wp_grndbnce.pdf)
- Basics of Signal Integrity White Paper  
[http://www.altera.com/literature/wp/wp\\_sgnIntgry.pdf](http://www.altera.com/literature/wp/wp_sgnIntgry.pdf)
- High-Speed Board Layout Guidelines  
<http://www.altera.com/literature/an/an224.pdf>
- Guidelines for Designing High-Speed FPGA PCBs  
<http://www.altera.com/literature/an/an315.pdf>

# More Information (cont.)

- Visit Altera's Memory Solution Center at:  
[www.altera.com/memory](http://www.altera.com/memory)



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**Thank You !**